## Notice of References Cited Application/Control No. 10/562,846 Examiner Yuwen Pan Applicant(s)/Patent Under Reexamination RATERMANN ET AL. Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-6,907,227	06-2005	Fujioka, Susumu	455/41.3
	В	US-			
	C	US-			
	D	US-			
	ш	US-			
	F.	US-			
	G	US-			
	Н	US-			
	1	US-			
	J	US-			
	К	US-			
	L	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP02002064512	02-2002	Japan	Fujita	
	0					
	Р					
	Q		•			
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## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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